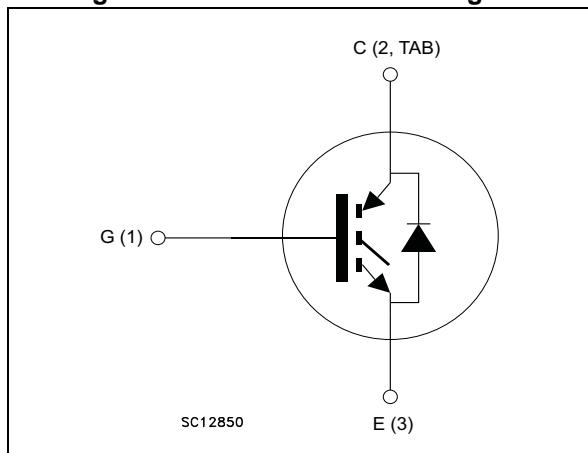


**Figure 1. Internal schematic diagram**



## Features

- Designed for soft commutation only
- Maximum junction temperature:  $T_J = 175^\circ\text{C}$
- Minimized tail current
- $V_{CE(\text{sat})} = 2.0 \text{ V (typ.)} @ I_C = 25 \text{ A}$
- Tight parameters distribution
- Safe paralleling
- Low  $V_F$  soft recovery co-packaged diode
- Low thermal resistance
- Lead free package

## Applications

- Induction heating
- Microwave oven
- Resonant converters

## Description

These IGBTs are developed using an advanced proprietary trench gate field-stop structure and performance is optimized in both conduction and switching losses. A freewheeling diode with a low drop forward voltage is co-packaged. The result is a product specifically designed to maximize efficiency for any resonant and soft-switching application.

**Table 1. Device summary**

Order code	Marking	Package	Packaging
STGW28IH125DF	G28IH125DF	TO-247	Tube
STGWT28IH125DF	G28IH125DF	TO-3P	Tube

## Contents

<b>1</b>	<b>Electrical ratings</b>	<b>3</b>
<b>2</b>	<b>Electrical characteristics</b>	<b>4</b>
2.1	Electrical characteristics (curves)	6
<b>3</b>	<b>Test circuits</b>	<b>11</b>
<b>4</b>	<b>Package mechanical data</b>	<b>12</b>
<b>5</b>	<b>Revision history</b>	<b>16</b>

# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{CES}$	Collector-emitter voltage ( $V_{GE} = 0$ )	1250	V
$I_C$	Continuous collector current at $T_C = 25^\circ\text{C}$	60	A
$I_C$	Continuous collector current at $T_C = 100^\circ\text{C}$	30	A
$I_{CP}^{(1)}$	Pulsed collector current	120	A
$V_{GE}$	Gate-emitter voltage	$\pm 20$	V
$I_F$	Continuous forward current at $T_C = 25^\circ\text{C}$	60	A
$I_F$	Continuous forward current at $T_C = 100^\circ\text{C}$	30	A
$I_{FP}^{(1)}$	Pulsed forward current	120	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	375	W
$T_{STG}$	Storage temperature range	- 55 to 150	$^\circ\text{C}$
$T_J$	Operating junction temperature	- 55 to 175	$^\circ\text{C}$

1. Pulse width limited by maximum junction temperature.

**Table 3. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thJC}$	Thermal resistance junction-case IGBT	0.4	$^\circ\text{C}/\text{W}$
$R_{thJC}$	Thermal resistance junction-case diode	1.47	$^\circ\text{C}/\text{W}$
$R_{thJA}$	Thermal resistance junction-ambient	50	$^\circ\text{C}/\text{W}$

## 2 Electrical characteristics

$T_J = 25^\circ\text{C}$  unless otherwise specified.

Table 4. Static characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{CES}}$	Collector-emitter breakdown voltage ( $V_{GE} = 0$ )	$I_C = 2 \text{ mA}$	1250			V
$V_{CE(\text{sat})}$	Collector-emitter saturation voltage	$V_{GE} = 15 \text{ V}, I_C = 25 \text{ A}$		2	2.5	V
		$V_{GE} = 15 \text{ V}, I_C = 25 \text{ A}$ $T_J = 125^\circ\text{C}$		2.2		
		$V_{GE} = 15 \text{ V}, I_C = 25 \text{ A}$ $T_J = 175^\circ\text{C}$		2.3		
		$V_{GE} = 15 \text{ V}, I_C = 50 \text{ A}$		2.65		
$V_F$	Forward on-voltage	$I_F = 25 \text{ A}$		1.2	1.6	V
		$I_F = 50 \text{ A}$		1.45		
		$I_F = 25 \text{ A}$ $T_J = 125^\circ\text{C}$		1.2		
		$I_F = 25 \text{ A}$ $T_J = 175^\circ\text{C}$		1.2		
$V_{GE(\text{th})}$	Gate threshold voltage	$V_{CE} = V_{GE}, I_C = 1 \text{ mA}$	5	6	7	V
$I_{CES}$	Collector cut-off current ( $V_{GE} = 0$ )	$V_{CE} = 1250 \text{ V}$			25	$\mu\text{A}$
$I_{GES}$	Gate-emitter leakage current ( $V_{CE} = 0$ )	$V_{GE} = \pm 20 \text{ V}$			250	nA

Table 5. Dynamic characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{ies}$	Input capacitance	$V_{CE} = 25 \text{ V}, f = 1 \text{ MHz},$ $V_{GE} = 0$	-	2035	-	pF
$C_{oes}$	Output capacitance		-	139	-	pF
$C_{res}$	Reverse transfer capacitance		-	52	-	pF
$Q_g$	Total gate charge	$V_{CC} = 960 \text{ V}, I_C = 25 \text{ A},$ $V_{GE} = 15 \text{ V}$ , see <a href="#">Figure 25</a>	-	114	-	nC
$Q_{ge}$	Gate-emitter charge		-	11	-	nC
$Q_{gc}$	Gate-collector charge		-	69	-	nC

**Table 6. IGBT switching characteristics (inductive load)**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(\text{off})}$	Turn-off delay time	$V_{CE} = 600 \text{ V}, I_C = 25 \text{ A}, R_G = 10 \Omega, V_{GE} = 15 \text{ V}$ , see <a href="#">Figure 23</a>	-	128	-	ns
$t_f$	Current fall time		-	82	-	ns
$E_{\text{off}}^{(1)}$	Turn-off switching losses		-	0.72	-	mJ
$t_{d(\text{off})}$	Turn-off delay time	$V_{CE} = 600 \text{ V}, I_C = 25 \text{ A}, R_G = 10 \Omega, V_{GE} = 15 \text{ V}, T_J = 175 \text{ }^\circ\text{C}$ , see <a href="#">Figure 23</a>	-	132	-	ns
$t_f$	Current fall time		-	190	-	ns
$E_{\text{off}}^{(1)}$	Turn-off switching losses		-	1.53	-	mJ

1. Turn-off losses include also the tail of the collector current.

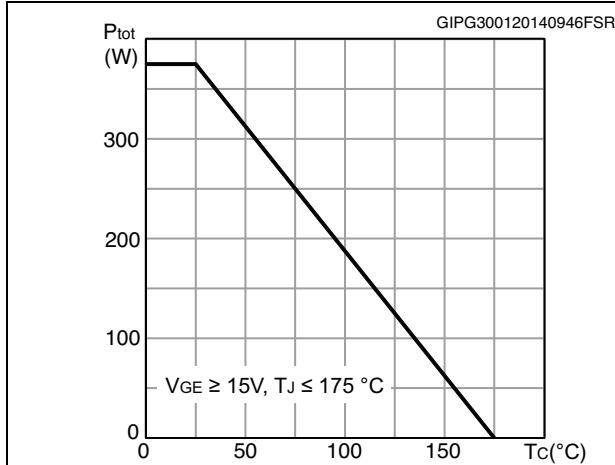
**Table 7. IGBT switching characteristics (capacitive load)**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$E_{\text{off}}^{(1)}$	Turn-off switching losses	$V_{CC} = 900 \text{ V}, R_G = 10 \Omega, I_C = 50 \text{ A}, L = 500 \mu\text{H}, C_{\text{ssub}} = 330 \text{ nF}$ , see <a href="#">Figure 24</a>	-	230	-	$\mu\text{J}$
		$V_{CC} = 900 \text{ V}, R_G = 10 \Omega, I_C = 50 \text{ A}, L = 500 \mu\text{H}, C_{\text{ssub}} = 330 \text{ nF}, T_J = 175 \text{ }^\circ\text{C}$ , see <a href="#">Figure 24</a>	-	520	-	

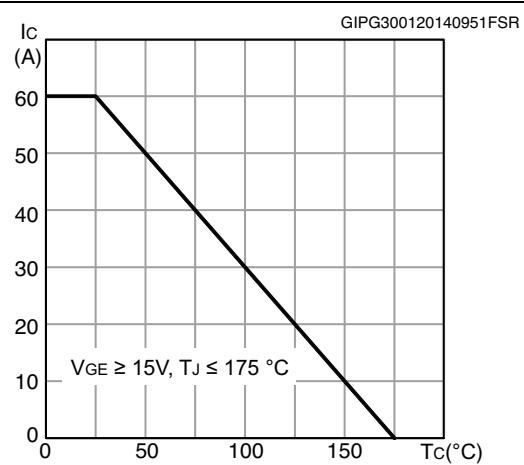
1. Turn-off losses include also the tail of the collector current.

## 2.1 Electrical characteristics (curves)

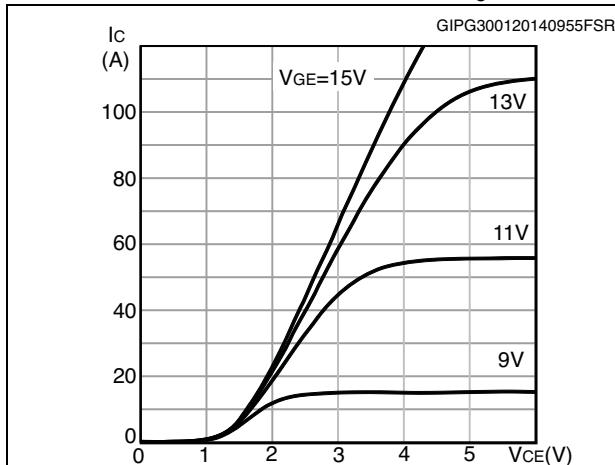
**Figure 2. Power dissipation vs. case temperature**



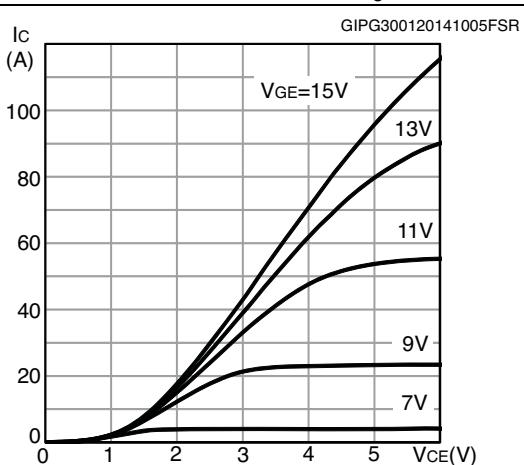
**Figure 3. Collector current vs. case temperature**



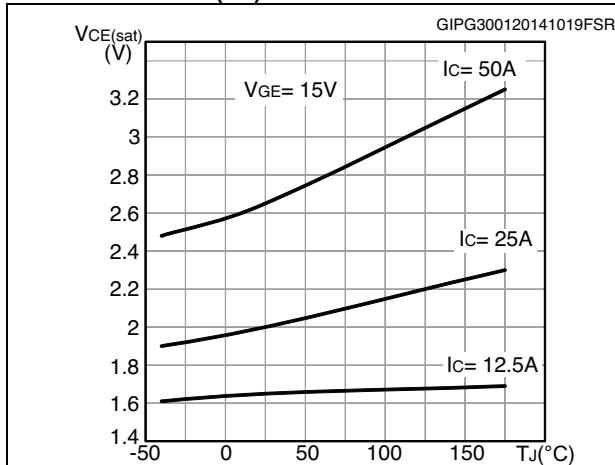
**Figure 4. Output characteristics ( $T_J = 25^{\circ}C$ )**



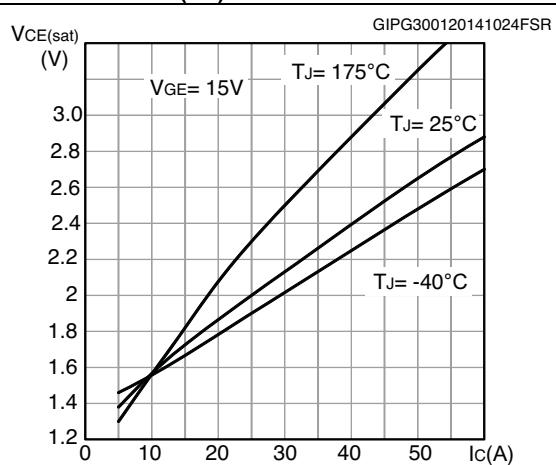
**Figure 5. Output characteristics ( $T_J = 175^{\circ}C$ )**

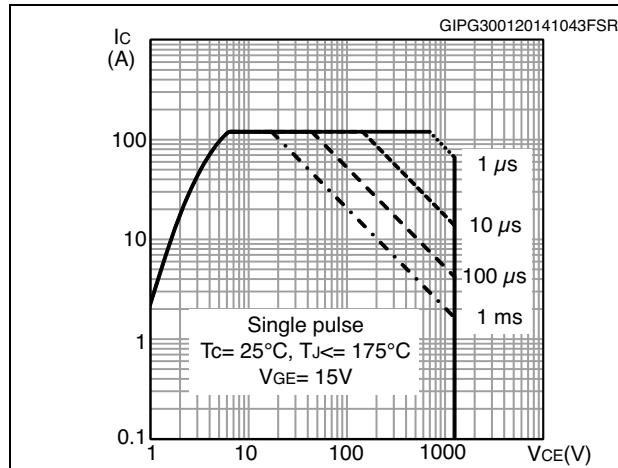
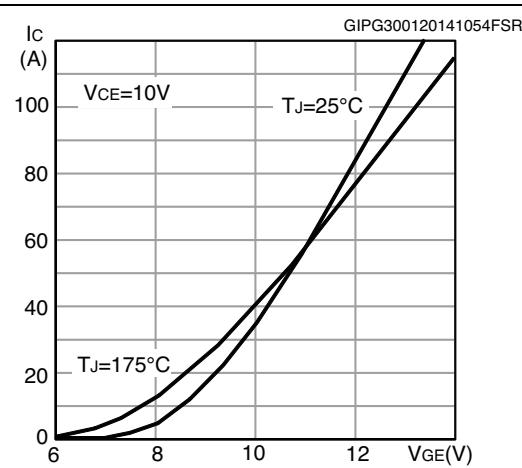
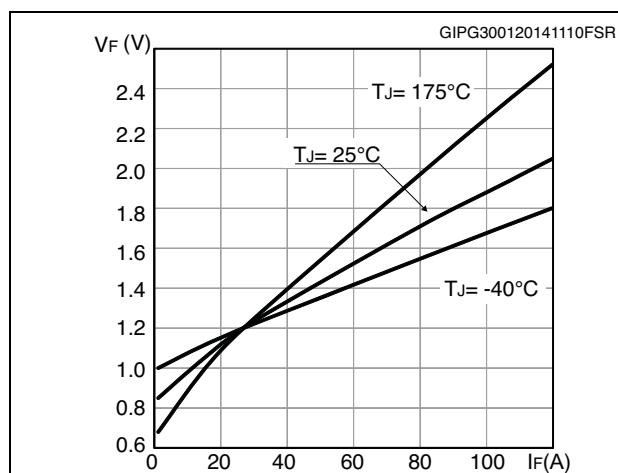
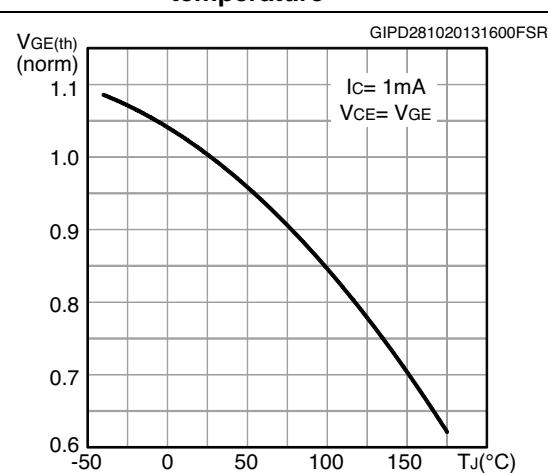
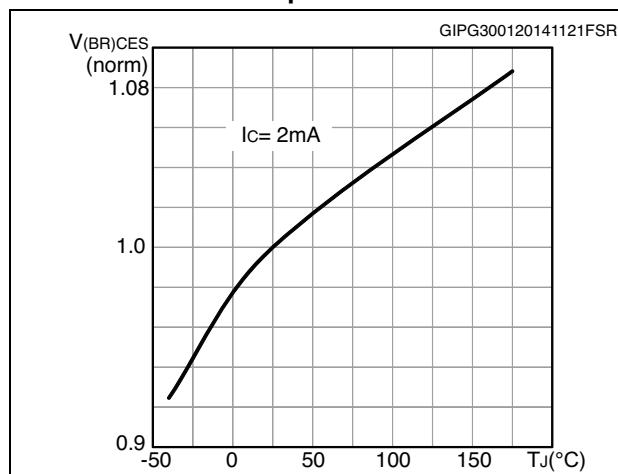
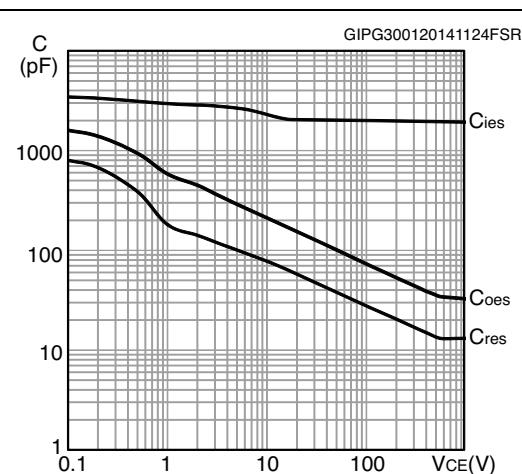


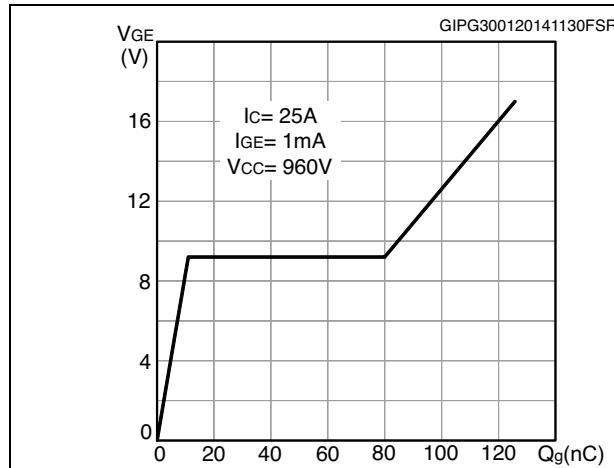
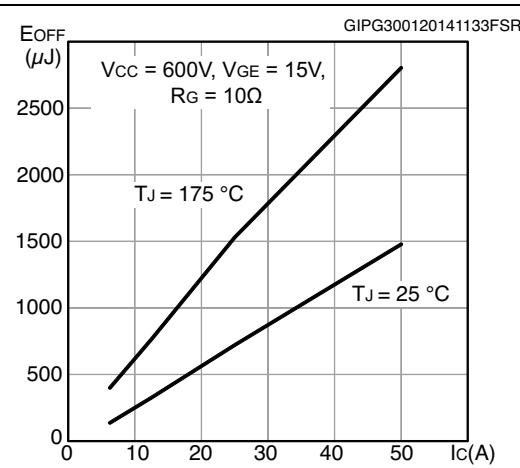
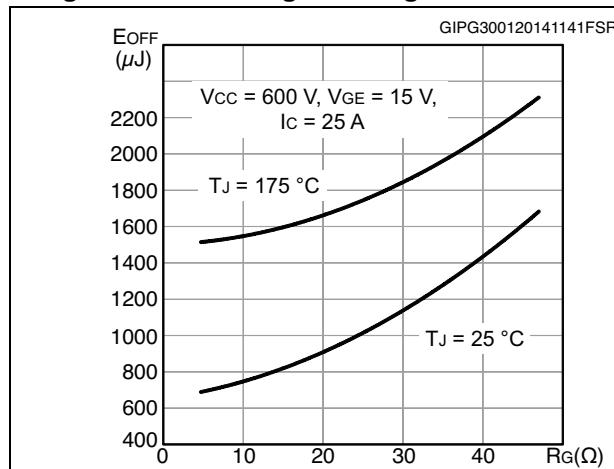
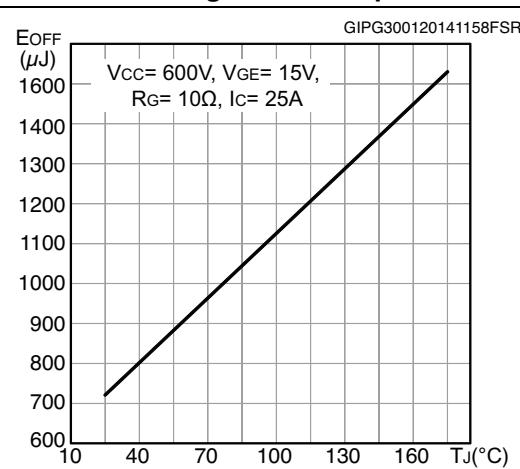
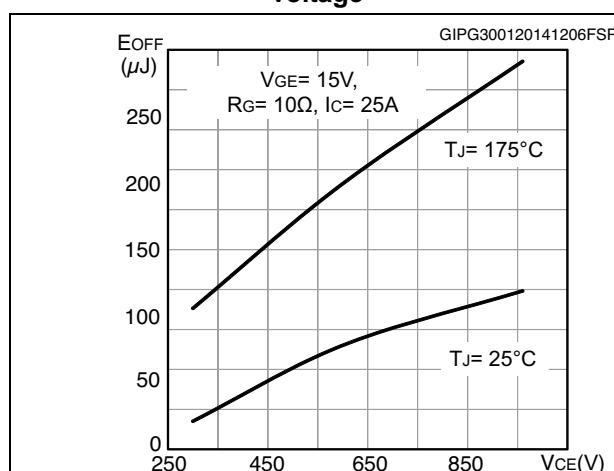
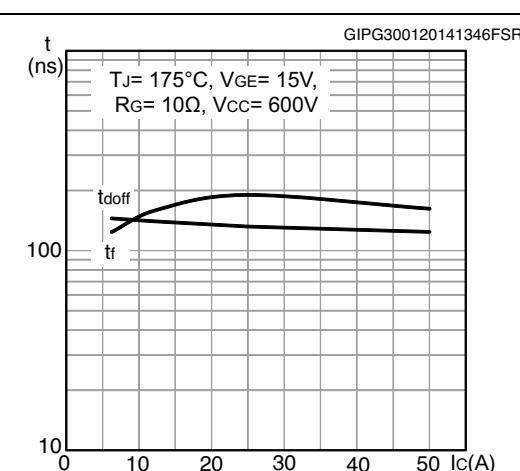
**Figure 6.  $V_{CE(sat)}$  vs. junction temperature**



**Figure 7.  $V_{CE(sat)}$  vs. collector current**



**Figure 8. Forward bias safe operating area****Figure 9. Transfer characteristics****Figure 10. Diode  $V_F$  vs. forward current****Figure 11. Normalized  $V_{GE(th)}$  vs junction temperature****Figure 12. Normalized  $V_{(BR)CES}$  vs. junction temperature****Figure 13. Capacitance variation**

**Figure 14. Gate charge vs. gate-emitter voltage****Figure 15. Switching loss vs collector current****Figure 16. Switching loss vs gate resistance****Figure 17. Switching loss vs temperature****Figure 18. Switching loss vs collector-emitter voltage****Figure 19. Switching times vs. collector current**

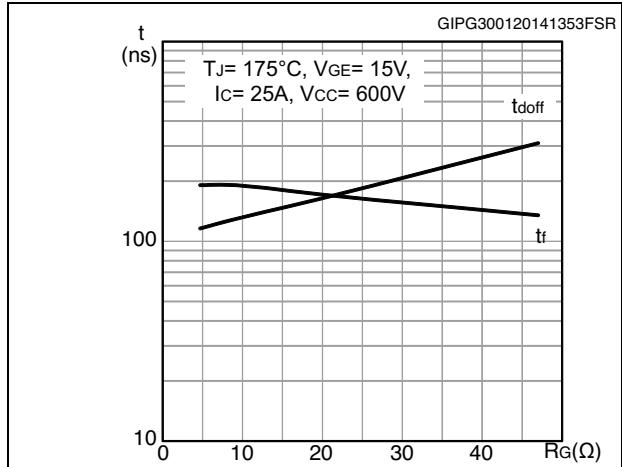
**Figure 20. Switching times vs. gate resistance**

Figure 21. Thermal impedance for IGBT

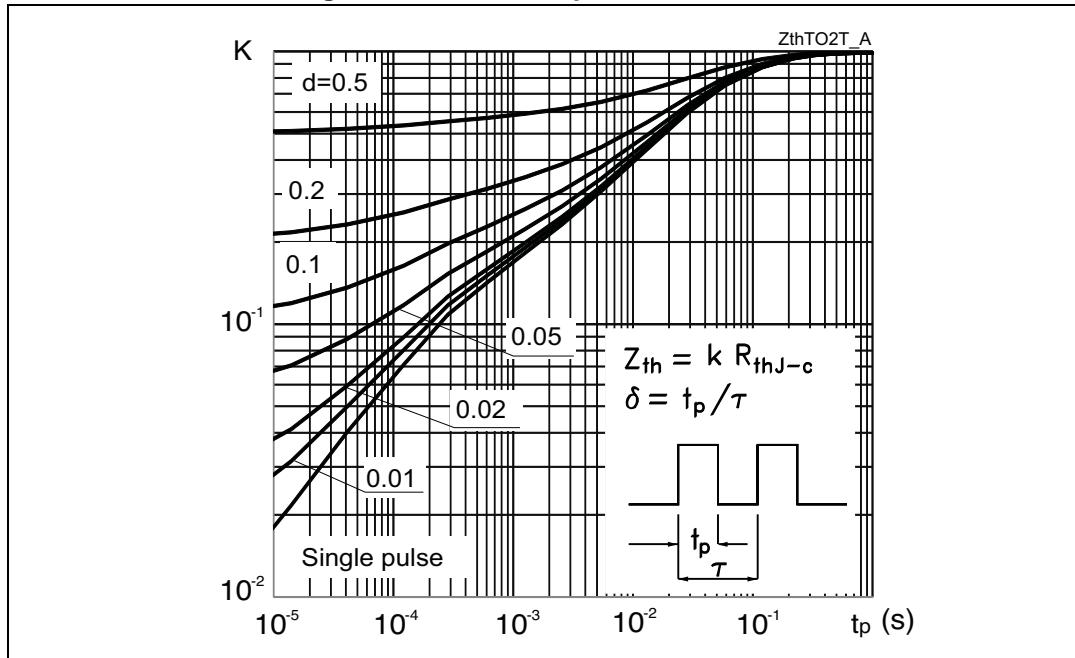
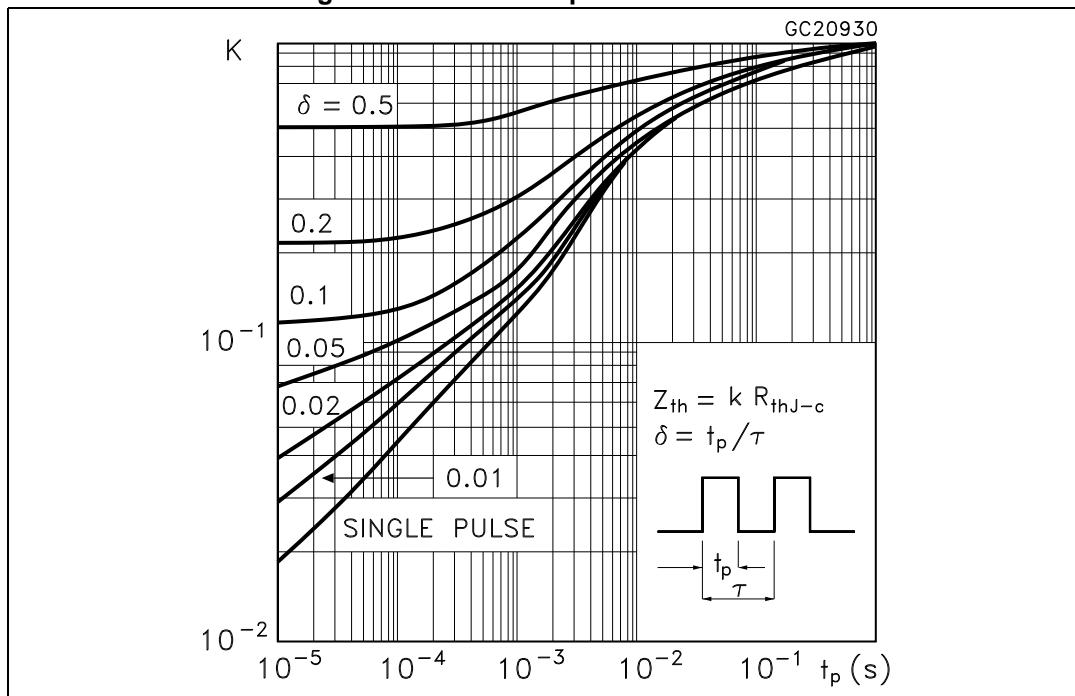
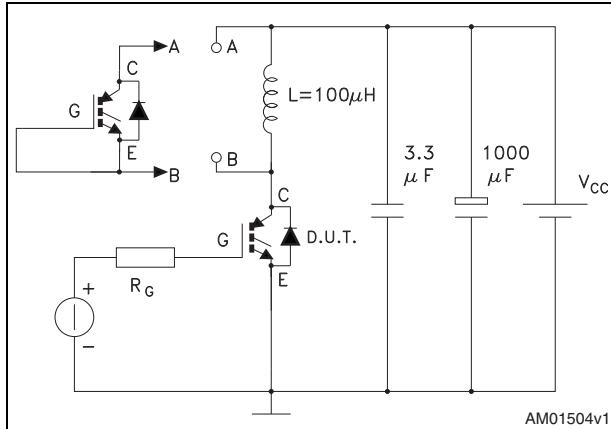


Figure 22. Thermal impedance for diode

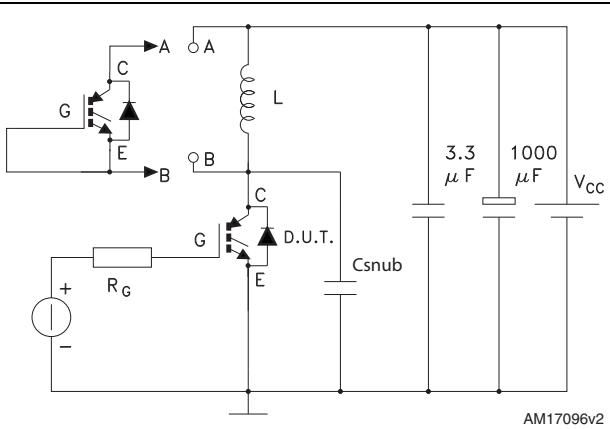


### 3 Test circuits

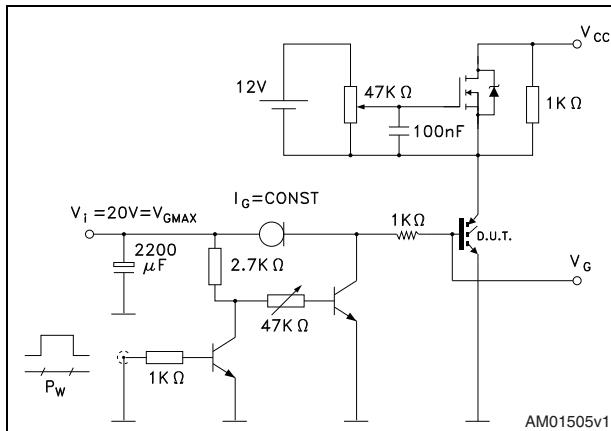
**Figure 23. Test circuit for inductive load switching**



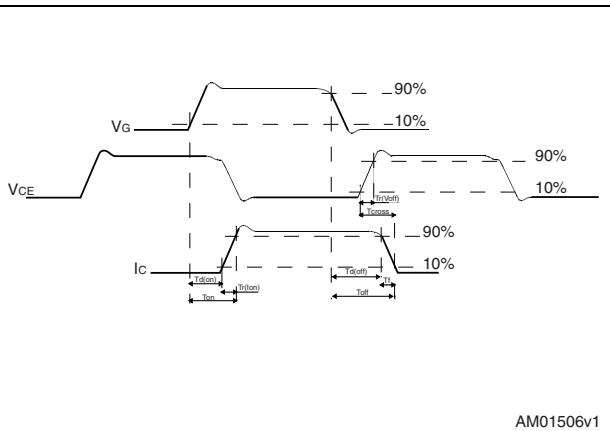
**Figure 24. Test circuit for capacitive load switching**



**Figure 25. Gate charge test circuit**



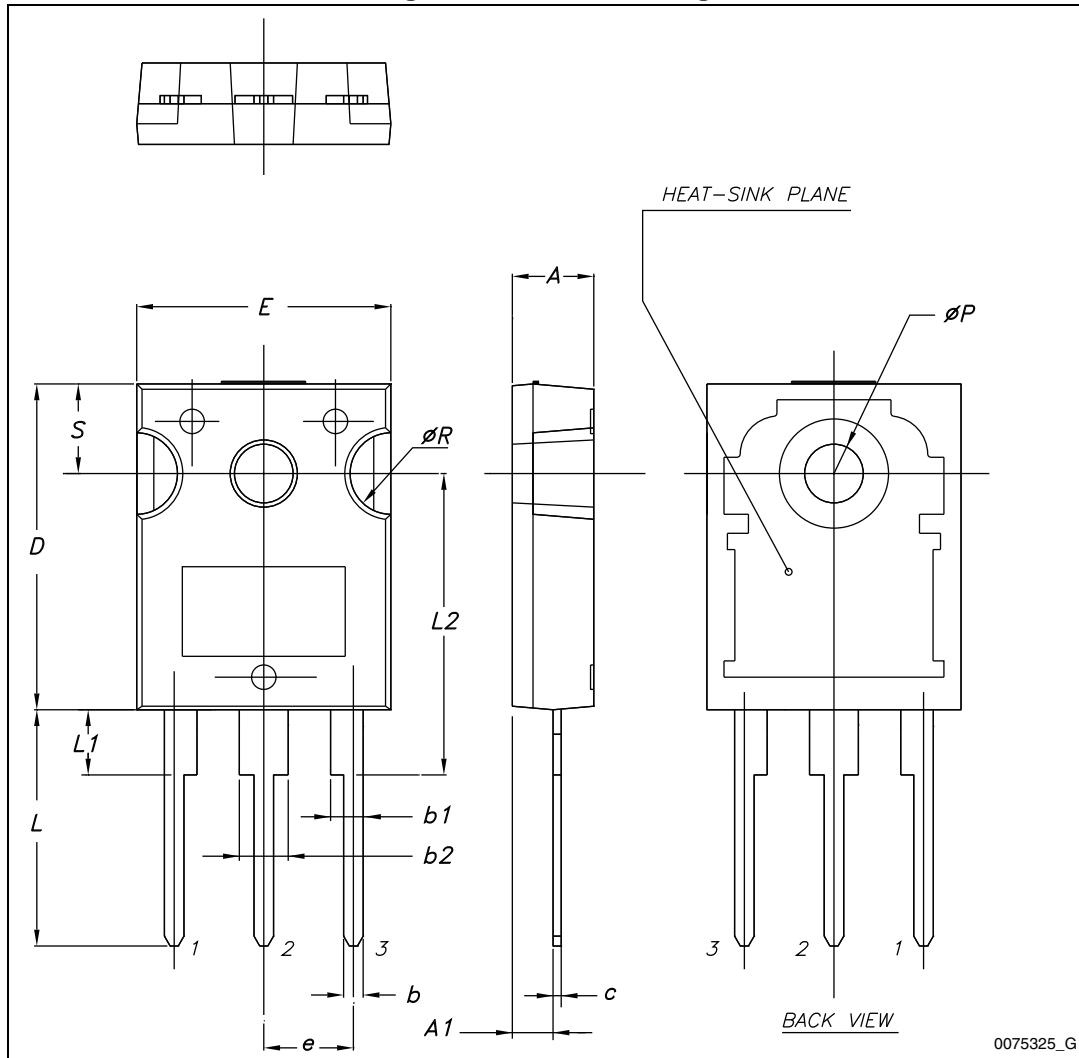
**Figure 26. Switching waveform**



## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
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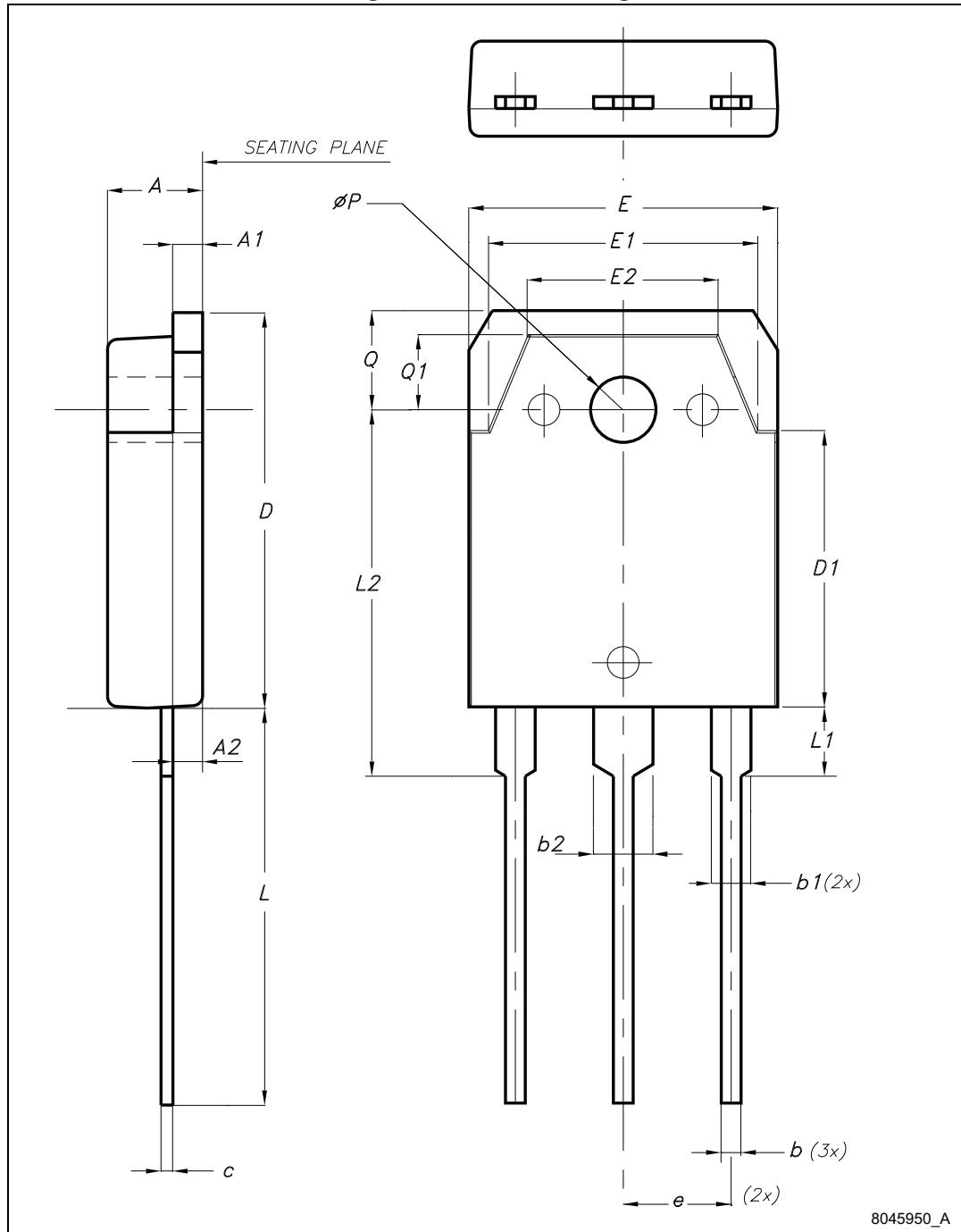
Figure 27. TO-247 drawing



**Table 8. TO-247 mechanical data**

Dim.	mm.		
	Min.	Typ.	Max.
A	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
c	0.40		0.80
D	19.85		20.15
E	15.45		15.75
e	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S	5.30	5.50	5.70

Figure 28. TO-3P drawing



**Table 9. TO-3P mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	4.60		5
A1	1.45	1.50	1.65
A2	1.20	1.40	1.60
b	0.80	1	1.20
b1	1.80		2.20
b2	2.80		3.20
c	0.55	0.60	0.75
D	19.70	19.90	20.10
D1		13.90	
E	15.40		15.80
E1		13.60	
E2		9.60	
e	5.15	5.45	5.75
L	19.50	20	20.50
L1		3.50	
L2	18.20	18.40	18.60
øP	3.10		3.30
Q		5	
Q1		3.80	

## 5 Revision history

Table 10. Document revision history

Date	Revision	Changes
20-Jan-2014	1	Initial release.
03-Feb-2014	2	Document status promoted from preliminary to production data. Updated <a href="#">Table 2: Absolute maximum ratings</a> , <a href="#">Table 4: Static characteristics</a> , <a href="#">Table 5: Dynamic characteristics</a> , <a href="#">Table 6: IGBT switching characteristics (inductive load)</a> and <a href="#">Table 7: IGBT switching characteristics (capacitive load)</a> . Inserted <a href="#">Section 2.1: Electrical characteristics (curves)</a> . Minor text changes.

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